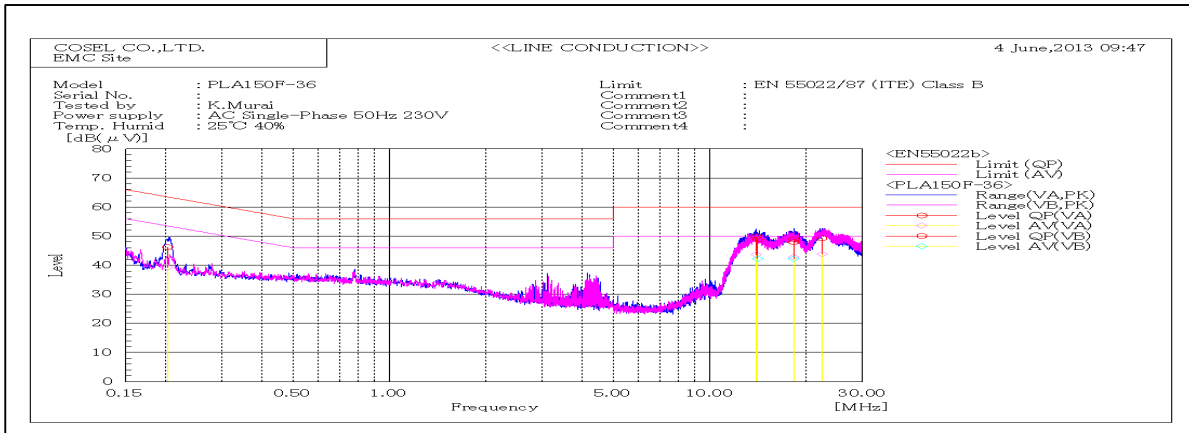
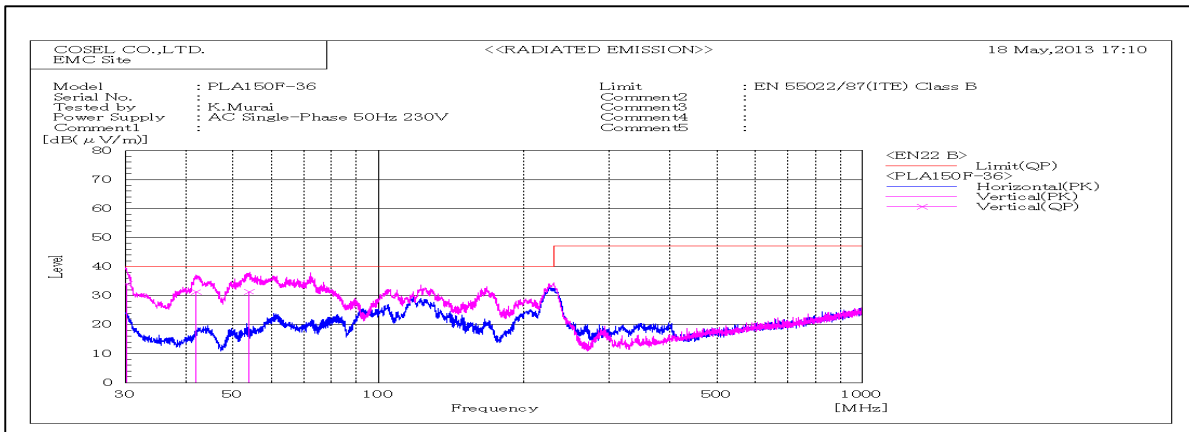


DATA SHEET		Date	24-Jun-13
Model	PLA150F-36	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Murai



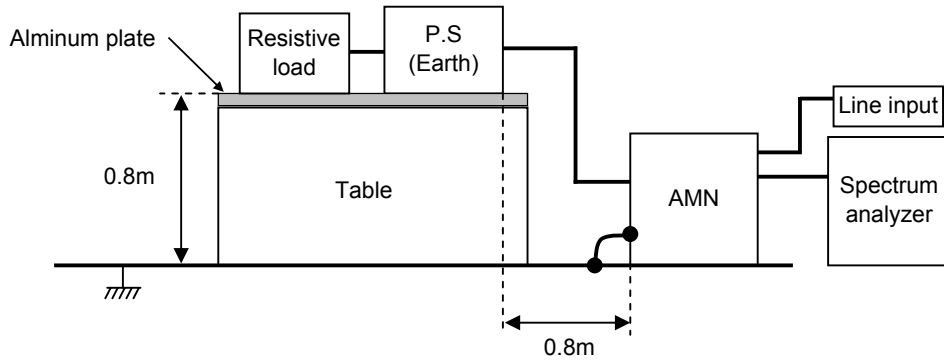
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.20296	LA	26.1	19.1	20.2	46.3	39.3	63.5	53.5	17.2	14.2	Pass	
13.9515	LA	28.9	22.6	21	49.9	43.6	60	50	10.1	6.4	Pass	
14.10115	LB	27.8	21.2	21	48.8	42.2	60	50	11.2	7.8	Pass	
18.28655	LB	26.7	21	21.2	47.9	42.2	60	50	12.1	7.8	Pass	
18.33765	LA	27.6	21.6	21.2	48.8	42.8	60	50	11.2	7.2	Pass	
22.4142	LA	28.2	22.8	21.1	49.3	43.9	60	50	10.7	6.1	Pass	



Frequency MHz	Polarization	Stability	Reading	Space Loss dB	Level	Limit	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV)		dB(mW)	dB(mW)					
30.155	V	Stable	47.5	-13.5	34	40	6	Pass	106	274	
42.005	V	Stable	47.5	-16.2	31.3	40	8.7	Pass	129	18	
53.951	V	Stable	55.1	-23.8	31.3	40	8.7	Pass	104	301	

DATA SHEET		Date	24-Jun-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Murai

1. Line conduction



2. Radiated emission

